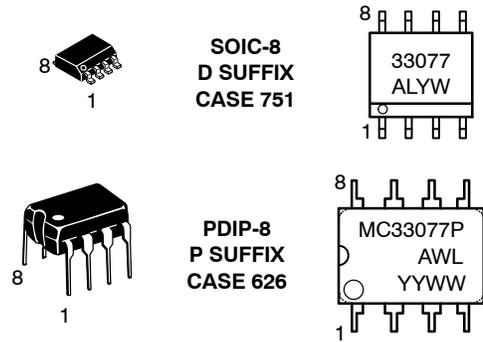# Low Noise Dual Operational Amplifier

## MC33077

The MC33077 is a precision high quality, high frequency, low noise monolithic dual operational amplifier employing innovative bipolar design techniques. Precision matching coupled with a unique analog resistor trim technique is used to obtain low input offset voltages. Dual-doublet frequency compensation techniques are used to enhance the gain bandwidth product of the amplifier. In addition, the MC33077 offers low input noise voltage, low temperature coefficient of input offset voltage, high slew rate, high AC and DC open loop voltage gain and low supply current drain. The all NPN transistor output stage exhibits no deadband cross-over distortion, large output voltage swing, excellent phase and gain margins, low open loop output impedance and symmetrical source and sink AC frequency performance.

The MC33077 is available in plastic DIP and SOIC-8 packages (P and D suffixes).
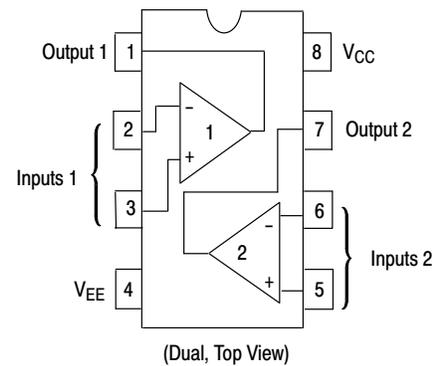
### Features

- Low Voltage Noise: 4.4 nV/$\sqrt{\text{Hz}}$ @ 1.0 kHz
- Low Input Offset Voltage: 0.2 mV
- Low TC of Input Offset Voltage: 2.0 $\mu$V/°C
- High Gain Bandwidth Product: 37 MHz @ 100 kHz
- High AC Voltage Gain: 370 @ 100 kHz
  1850 @ 20 kHz
- Unity Gain Stable: with Capacitance Loads to 500 pF
- High Slew Rate: 11 V/$\mu$s
- Low Total Harmonic Distortion: 0.007%
- Large Output Voltage Swing: +14 V to −14.7 V
- High DC Open Loop Voltage Gain: 400 k (112 dB)
- High Common Mode Rejection: 107 dB
- Low Power Supply Drain Current: 3.5 mA
- Dual Supply Operation: ±2.5 V to ±18 V
- Pb-Free Package is Available

**MARKING DIAGRAMS**



**SOIC-8**
**D SUFFIX**
**CASE 751**

```
8 ┌────────┐
  │ 33077  │
  │ ALYW   │
1 └────────┘
```

**PDIP-8**
**P SUFFIX**
**CASE 626**

```
8 ┌──────────┐
  │ MC33077P │
  │ AWL      │
  │ YYWW     │
1 └──────────┘
```

| A | = Assembly Location |
| WL, L | = Wafer Lot |
| YY, Y | = Year |
| WW, W | = Work Week |

**PIN CONNECTIONS**



Output 1 — 1  | 8 — $V_{CC}$
Inputs 1 { 2, 3 — 1  | 7 — Output 2
$V_{EE}$ — 4 | 2 — 6, 5 } Inputs 2

(Dual, Top View)

**ORDERING INFORMATION**

| Device | Package | Shipping[†] |
|---|---|---|
| MC33077DR2G | SOIC-8 (Pb-Free) | 2500 Tape & Reel |

**DISCONTINUED** (Note 1)

| | | |
|---|---|---|
| MC33077D | SOIC-8 | 98 Units/Rail |
| MC33077DR2 | | 2500 / Tape & Reel |
| MC33077P | PDIP-8 | 50 Units/Rail |

† For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

1. **DISCONTINUED:** These devices are not available. Please contact your **onsemi** representative for information. The most current information on these devices may be available on www.onsemi.com.
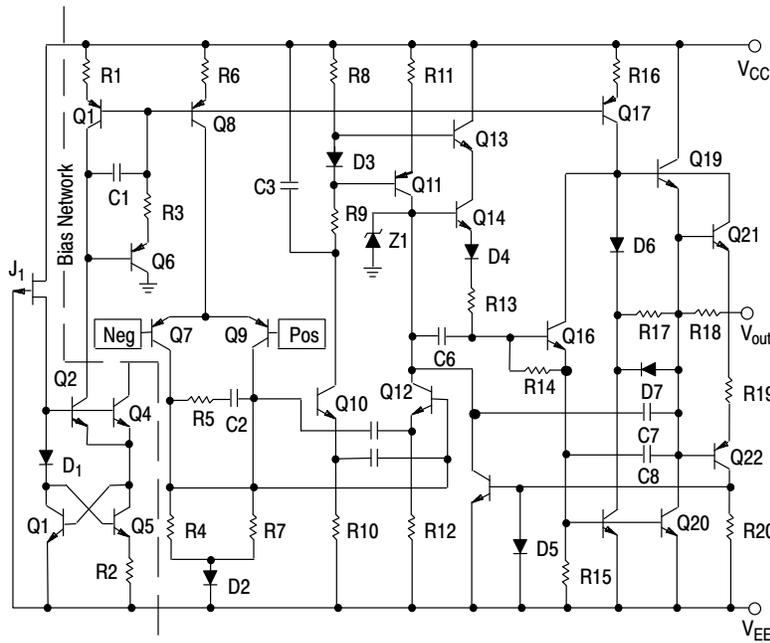
# MC33077



**Figure 1. Representative Schematic Diagram** (Each Amplifier)

## MAXIMUM RATINGS

| Rating | Symbol | Value | Unit |
|---|---|---|---|
| Supply Voltage ($V_{CC}$ to $V_{EE}$) | $V_S$ | +36 | V |
| Input Differential Voltage Range | $V_{IDR}$ | (Note 2) | V |
| Input Voltage Range | $V_{IR}$ | (Note 2) | V |
| Output Short Circuit Duration (Note 3) | $t_{SC}$ | Indefinite | sec |
| Maximum Junction Temperature | $T_J$ | +150 | °C |
| Storage Temperature | $T_{stg}$ | −60 to +150 | °C |
| ESD Protection at any Pin<br>    – Human Body Model<br>    – Machine Model | $V_{esd}$ | <br>550<br>150 | V |
| Maximum Power Dissipation | $P_D$ | (Note 3) | mW |
| Operating Temperature Range | $T_A$ | −40 to + 85 | °C |

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

2. Either or both input voltages should not exceed $V_{CC}$ or $V_{EE}$ (See Applications Information).
3. Power dissipation must be considered to ensure maximum junction temperature ($T_J$) is not exceeded (See power dissipation performance characteristic, Figure 2).

**DC ELECTRICAL CHARACTERISTICS** ($V_{CC}$ = +15 V, $V_{EE}$ = −15 V, $T_A$ = 25 °C, unless otherwise noted.)

| Characteristics | Symbol | Min | Typ | Max | Unit |
|---|---|---|---|---|---|
| Input Offset Voltage ($R_S$ = 10 Ω, $V_{CM}$ = 0 V, $V_O$ = 0 V)<br>$T_A$ = +25 °C<br>$T_A$ = −40 °C to +85 °C | $|V_{IO}|$ | <br>–<br>– | <br>0.13<br>– | <br>1.0<br>1.5 | mV |
| Average Temperature Coefficient of Input Offset Voltage<br><br>$R_S$ = 10 Ω, $V_{CM}$ = 0 V, $V_O$ = 0 V, $T_A$ = −40 °C to +85 °C | $\Delta V_{IO}/\Delta T$ | <br><br>– | <br><br>2.0 | <br><br>– | μV/°C |
| Input Bias Current ($V_{CM}$ = 0 V, $V_O$ = 0 V)<br>$T_A$ = +25 °C<br>$T_A$ = −40 °C to +85 °C | $I_{IB}$ | <br>–<br>– | <br>280<br>– | <br>1000<br>1200 | nA |
| Input Offset Current ($V_{CM}$ = 0 V, $V_O$ = 0 V)<br>$T_A$ = +25 °C<br>$T_A$ = −40 °C to +85 °C | $I_{IO}$ | <br>–<br>– | <br>15<br>– | <br>180<br>240 | nA |
| Common Mode Input Voltage Range ($\Delta V_{IO}$ ,= 5.0 mV, $V_O$ = 0 V) | $V_{ICR}$ | ±13.5 | ±14 | – | V |
| Large Signal Voltage Gain ($V_O$ = ±1.0 V, $R_L$ = 2.0 kΩ)<br>$T_A$ = +25 °C<br>$T_A$ = −40 °C to +85 °C | $A_{VOL}$ | <br>150<br>125 | <br>400<br>– | <br>–<br>– | kV/V |
| Output Voltage Swing ($V_{ID}$ = ±1.0 V)<br>$R_L$ = 2.0 kΩ<br>$R_L$ = 2.0 kΩ<br>$R_L$ = 10 kΩ<br>$R_L$ = 10 kΩ | <br>$V_{O+}$<br>$V_{O-}$<br>$V_{O+}$<br>$V_{O-}$ | <br>+13.0<br>–<br>+13.4<br>– | <br>+13.6<br>−14.1<br>+14.0<br>−14.7 | <br>–<br>−13.5<br>–<br>−14.3 | V |
| Common Mode Rejection ($V_{in}$ = ±13 V) | CMR | 85 | 107 | – | dB |
| Power Supply Rejection (Note 4)<br><br>$V_{CC}/V_{EE}$ = +15 V/ −15 V to +5.0 V/ −5.0 V | PSR | <br><br>80 | <br><br>90 | <br><br>– | dB |
| Output Short Circuit Current ($V_{ID}$ = ±1.0 V, Output to Ground)<br>Source<br>Sink | $I_{SC}$ | <br>+10<br>−20 | <br>+26<br>−33 | <br>+60<br>+60 | mA |
| Power Supply Current ($V_O$ = 0 V, All Amplifiers)<br>$T_A$ = +25 °C<br>$T_A$ = −40 °C to +85 °C | $I_D$ | <br>–<br>– | <br>3.5<br>– | <br>4.5<br>4.8 | mA |

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.
4. Measured with $V_{CC}$ and $V_{EE}$ simultaneously varied.

**AC ELECTRICAL CHARACTERISTICS** ($V_{CC}$ = +15 V, $V_{EE}$ = −15 V, $T_A$ = 25 °C, unless otherwise noted.)

| Characteristics | Symbol | Min | Typ | Max | Unit |
|---|---|---|---|---|---|
| Slew Rate ($V_{in}$ = −10 V to +10 V, $R_L$ = 2.0 kΩ, $C_L$ = 100 pF, $A_V$ = +1.0) | SR | 8.0 | 11 | – | V/μs |
| Gain Bandwidth Product (f = 100 kHz) | GBW | 25 | 37 | – | MHz |
| AC Voltage Gain ($R_L$ = 2.0 kΩ, $V_O$ = 0 V)<br>    f = 100 kHz<br>    f = 20 kHz | $A_{VO}$ | <br>–<br>– | <br>370<br>1850 | <br>–<br>– | V/V |
| Unity Gain Bandwidth (Open Loop) | BW | – | 7.5 | – | MHz |
| Gain Margin ($R_L$ = 2.0 kΩ, $C_L$ = 10 pF) | $A_m$ | – | 10 | – | dB |
| Phase Margin ($R_L$ = 2.0 kΩ, $C_L$ = 10 pF) | $\varnothing_m$ | – | 55 | – | Deg |
| Channel Separation (f = 20 Hz to 20 kHz, $R_L$ = 2.0 kΩ, $V_O$ = 10 $V_{pp}$) | CS | – | −120 | – | dB |
| Power Bandwidth ($V_O$ = 27$_{p-p}$, $R_L$ = 2.0 kΩ, THD ≤ 1%) | $BW_p$ | – | 200 | – | kHz |
| Distortion ($R_L$ = 2.0 kΩ)<br>    $A_V$ = +1.0, f = 20 Hz to 20 kHz<br>        $V_O$ = 3.0 $V_{RMS}$<br>    $A_V$ = 2000, f = 20 kHz<br>        $V_O$ = 2.0 $V_{pp}$<br>        $V_O$ = 10 $V_{pp}$<br>    $A_V$ = 4000, f = 100 kHz<br>        $V_O$ = 2.0 $V_{pp}$<br>        $V_O$ = 10 $V_{pp}$ | THD | <br><br>–<br><br>–<br>–<br><br>–<br>– | <br><br>0.007<br><br>0.215<br>0.242<br><br>0.3.19<br>0.316 | <br><br>–<br><br>–<br>–<br><br>–<br>– | % |
| Open Loop Output Impedance ($V_O$ = 0 V, f = $f_U$) | $|Z_O|$ | – | 36 | – | Ω |
| Differential Input Resistance ($V_{CM}$ = 0 V) | $R_{in}$ | – | 270 | – | kΩ |
| Differential Input Capacitance ($V_{CM}$ = 0 V) | $C_{in}$ | – | 15 | – | pF |
| Equivalent Input Noise Voltage ($R_S$ = 100 Ω)<br>    f = 10 Hz<br>    f = 1.0 kHz | $e_n$ | <br>–<br>– | <br>6.7<br>4.4 | <br>–<br>– | nV/$\sqrt{Hz}$ |
| Equivalent Input Noise Current (f = 1.0 kHz)<br>    f = 10 Hz<br>    f = 1.0 kHz | $i_n$ | <br>–<br>– | <br>1.3<br>0.6 | <br>–<br>– | pA/$\sqrt{Hz}$ |
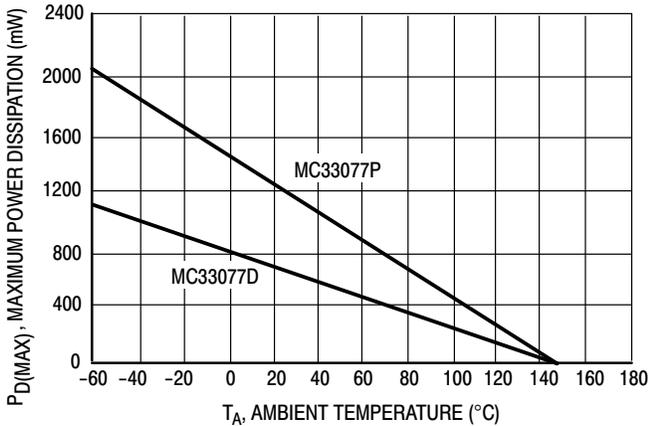


**Figure 2. Maximum Power Dissipation versus Temperature**
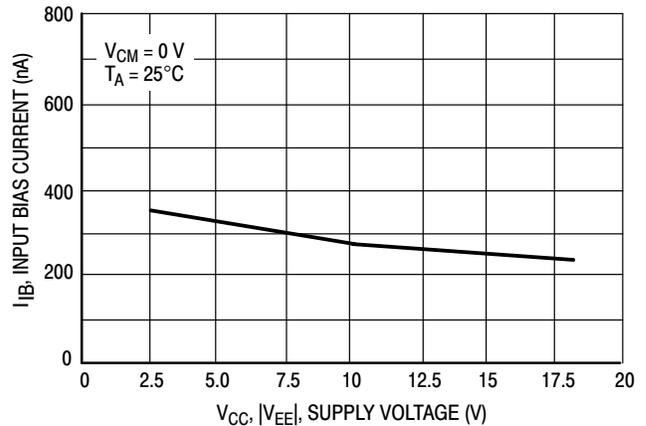


**Figure 3. Input Bias Current versus Supply Voltage**
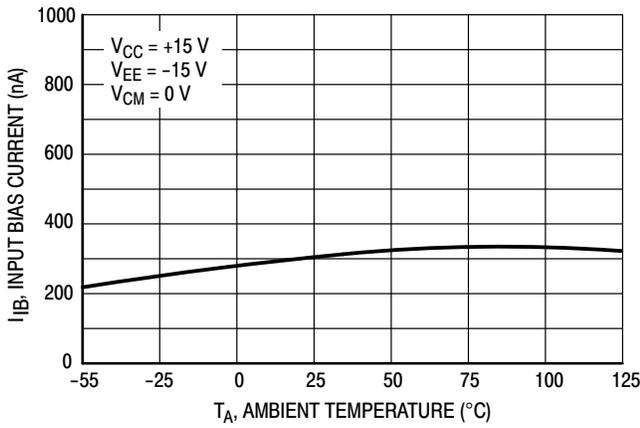
Figure 4. Input Bias Current
versus Temperature
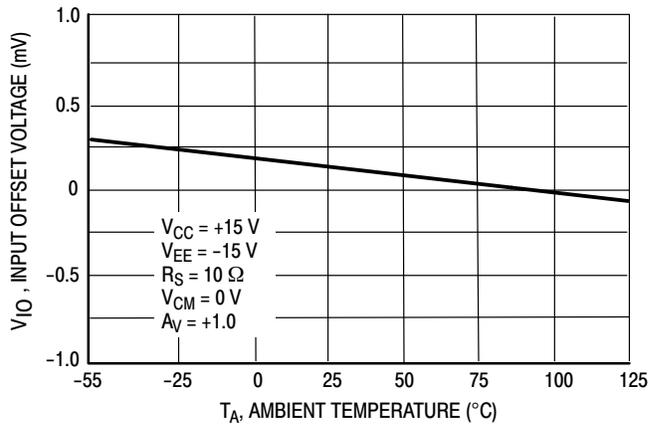


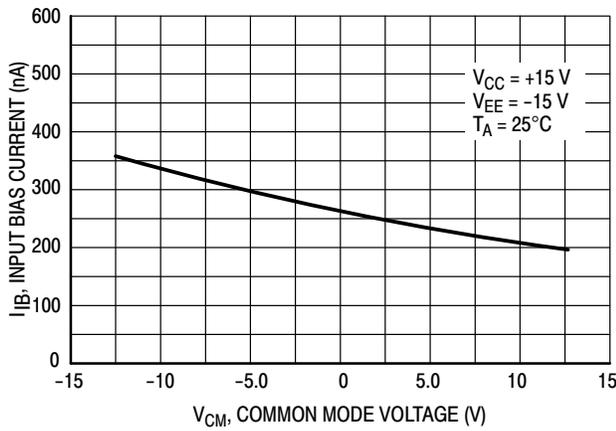Figure 5. Input Offset Voltage
versus Temperature



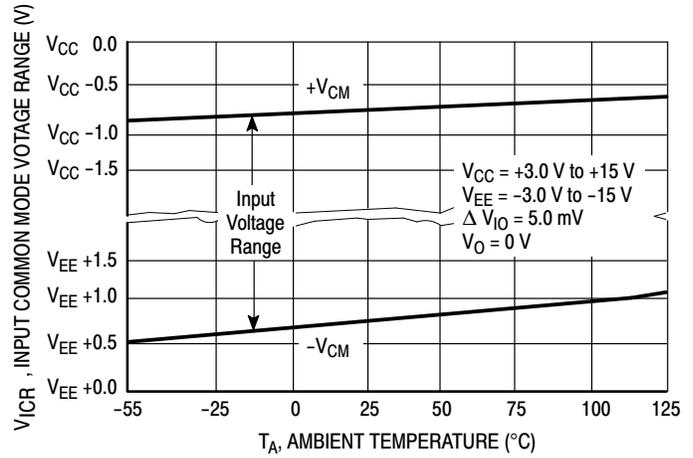Figure 6. Input Bias Current versus
Common Mode Voltage



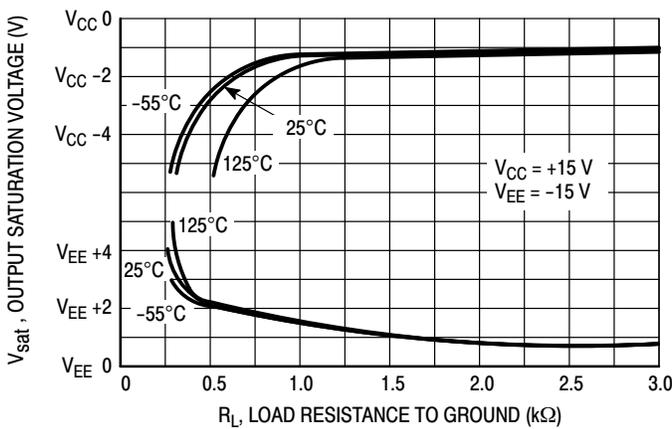Figure 7. Input Common Mode Voltage Range
versus Temperature



Figure 8. Output Saturation Voltage versus
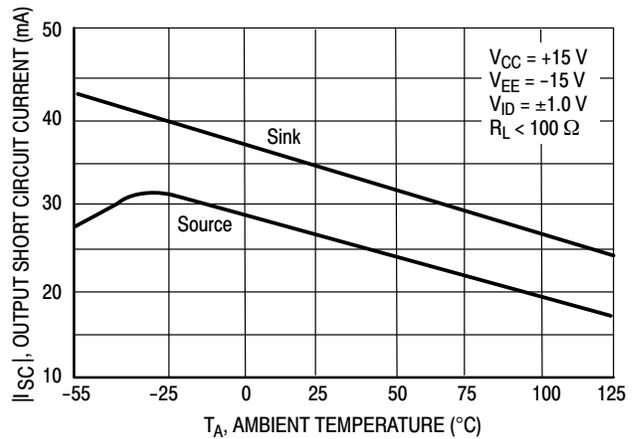Load Resistance to Ground



Figure 9. Output Short Circuit Current
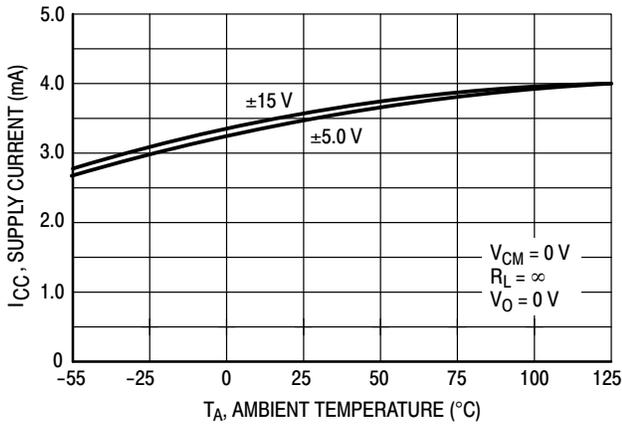versus Temperature
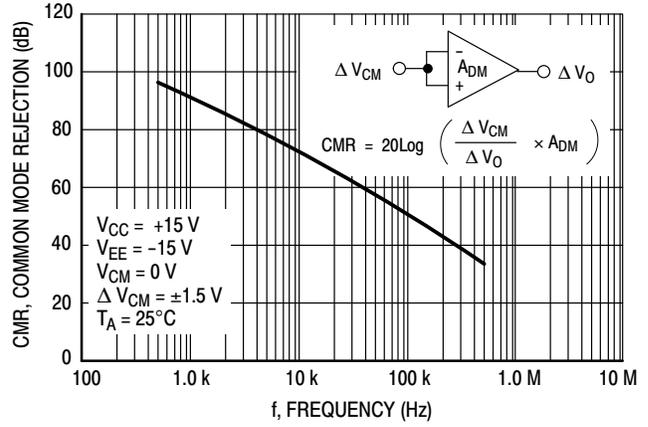
**Figure 10. Supply Current
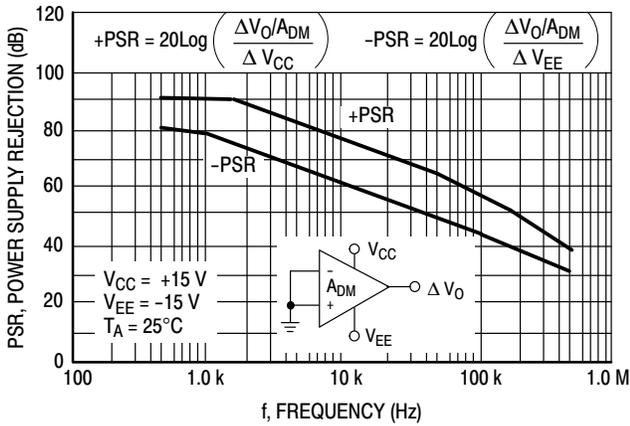versus Temperature**



**Figure 11. Common Mode Rejection
versus Frequency**



**Figure 12. Power Supply Rejection
versus Frequency**
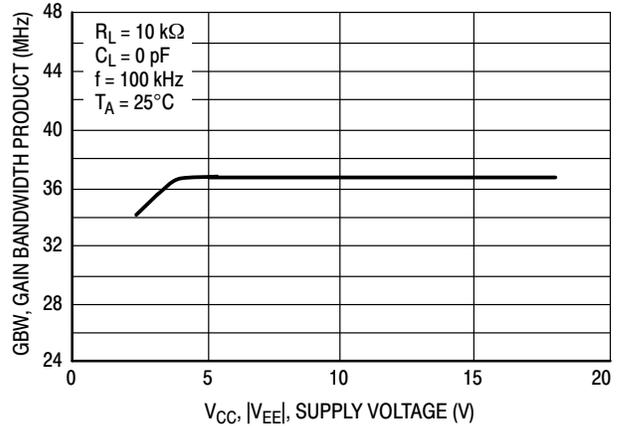


**Figure 13. Gain Bandwidth Product
versus Supply Voltage**
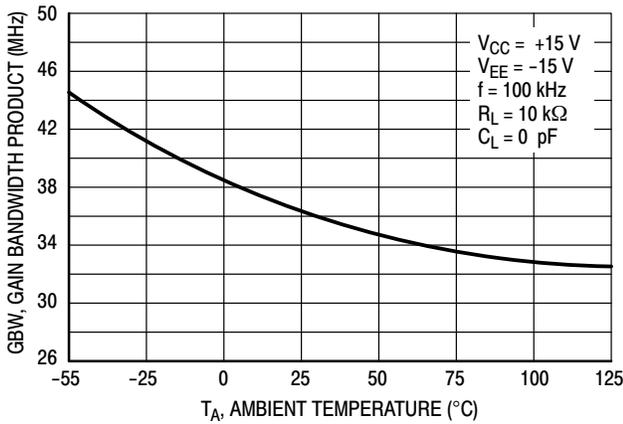


**Figure 14. Gain Bandwidth Product
versus Temperature**
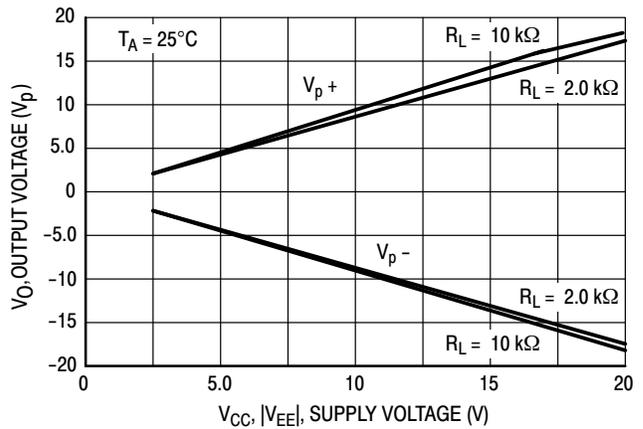


**Figure 15. Maximum Output Voltage
versus Supply Voltage**
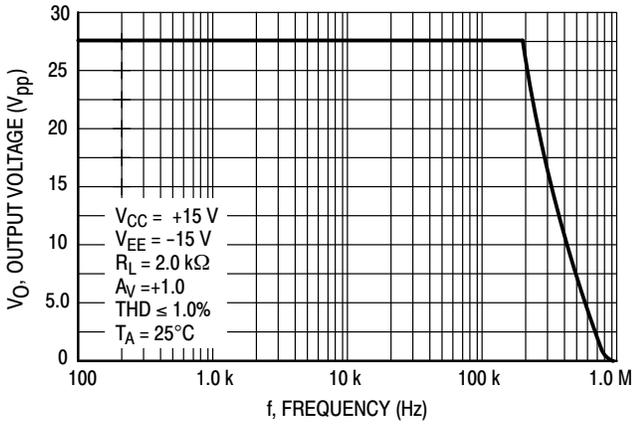
**Figure 16. Output Voltage
versus Frequency**
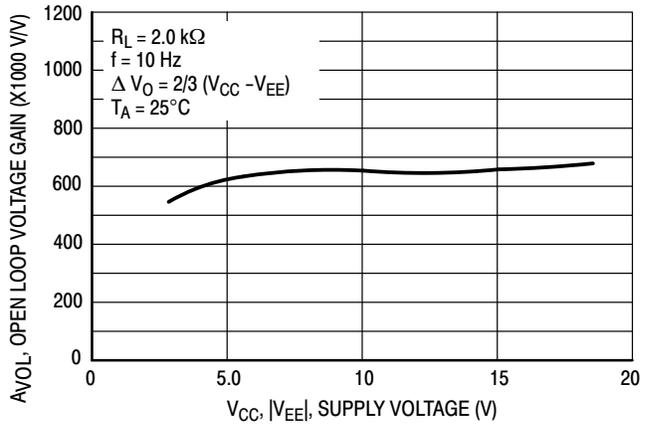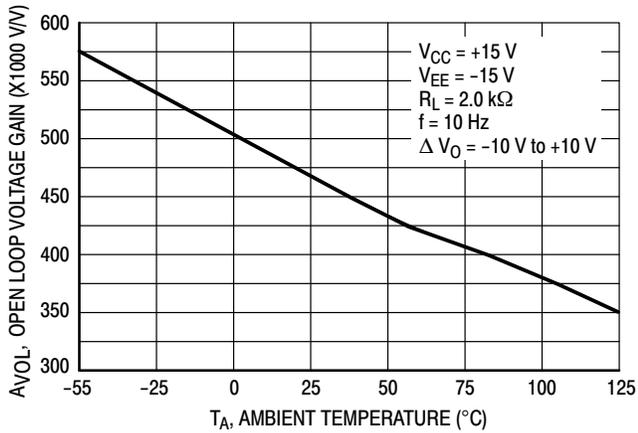


**Figure 17. Open Loop Voltage Gain
versus Supply Voltage**



**Figure 18. Open Loop Voltage Gain
versus Temperature**
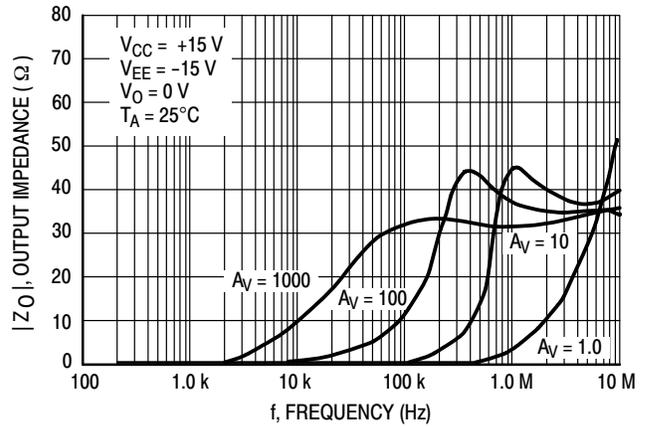


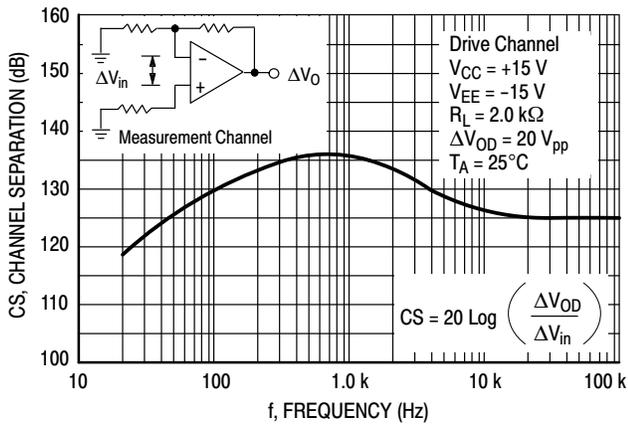**Figure 19. Output Impedance
versus Frequency**



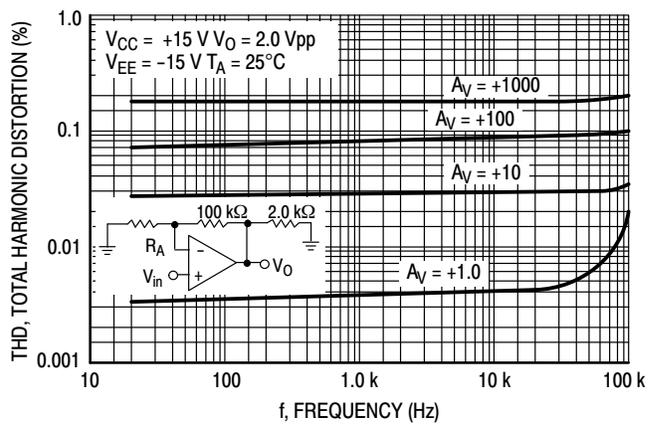**Figure 20. Channel Separation
versus Frequency**



**Figure 21. Total Harmonic Distortion
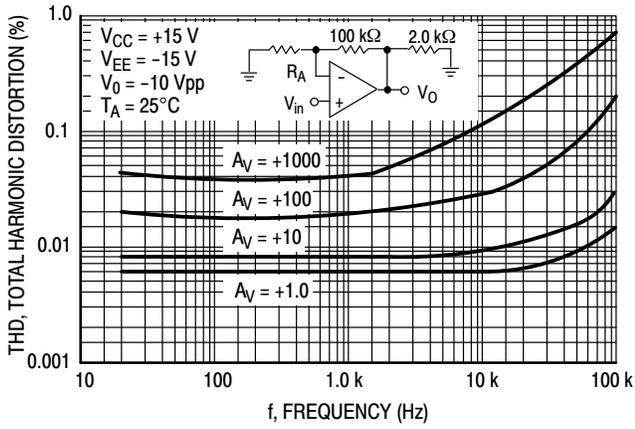versus Frequency**

# MC33077



**Figure 22. Total Harmonic Distortion versus Frequency**
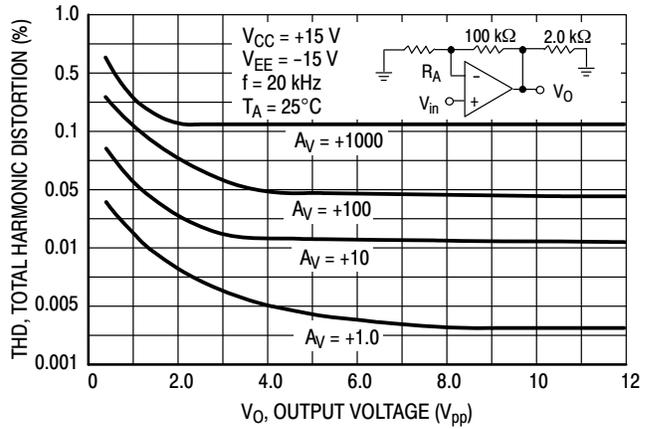


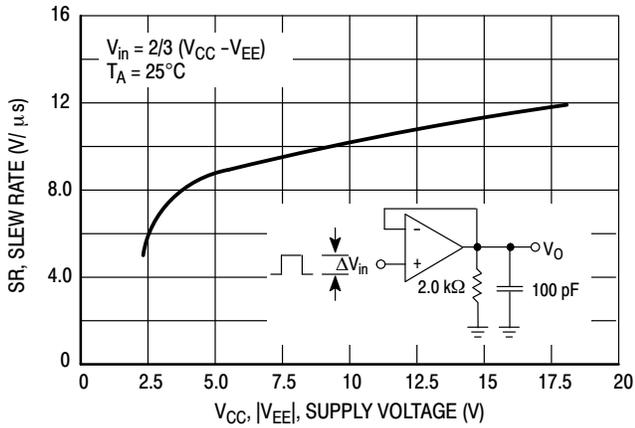**Figure 23. Total Harmonic Distortion versus Output Voltage**



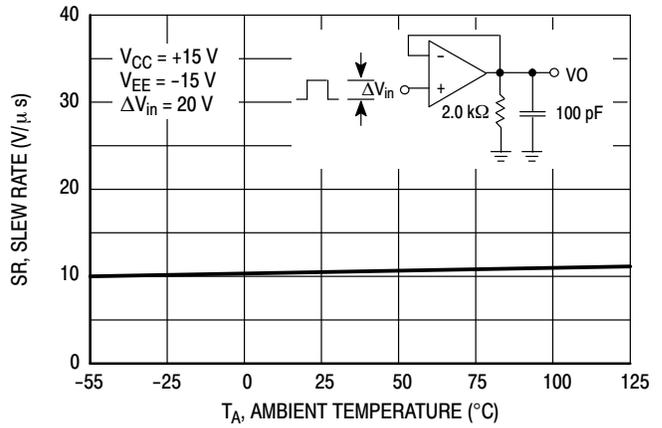**Figure 24. Slew Rate versus Supply Voltage**



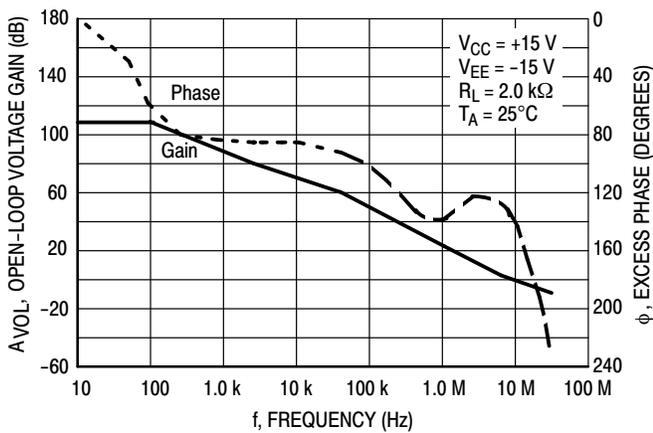**Figure 25. Slew Rate versus Temperature**



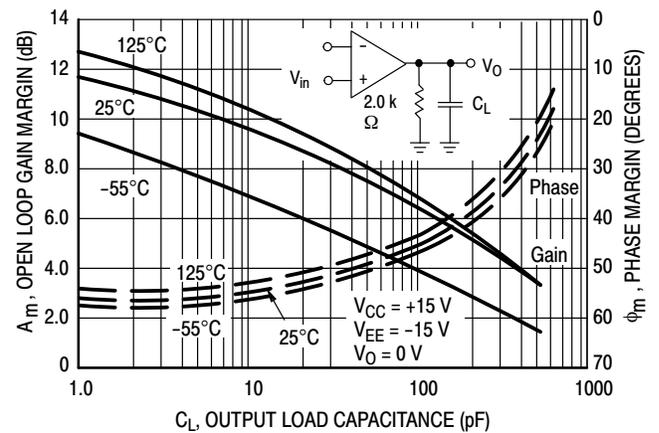**Figure 26. Voltage Gain and Phase versus Frequency**



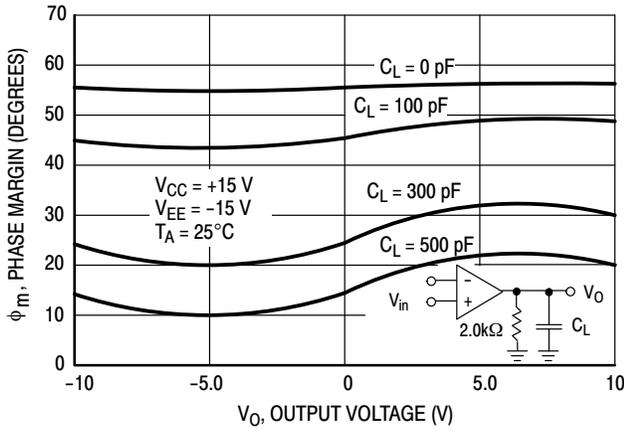**Figure 27. Open Loop Gain Margin and Phase Margin versus Output Load Capacitance**

**Figure 28. Phase Margin versus Output Voltage**
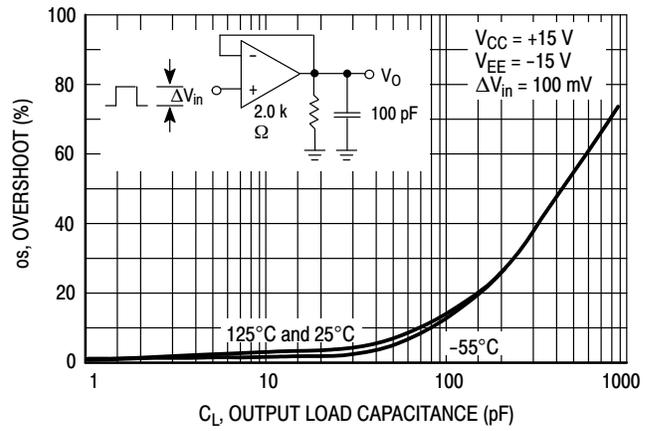


**Figure 29. Overshoot versus Output Load Capacitance**



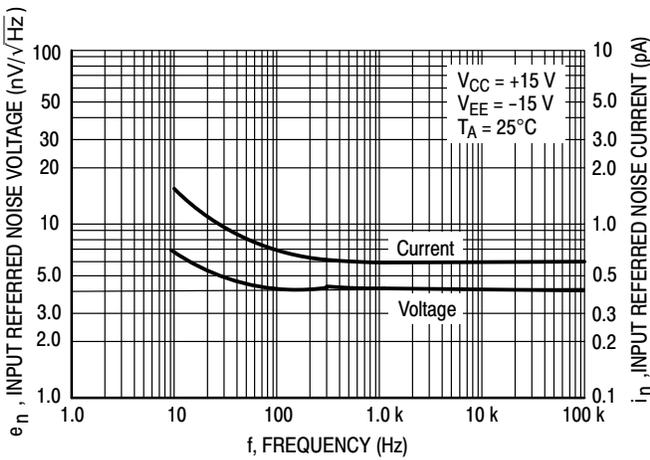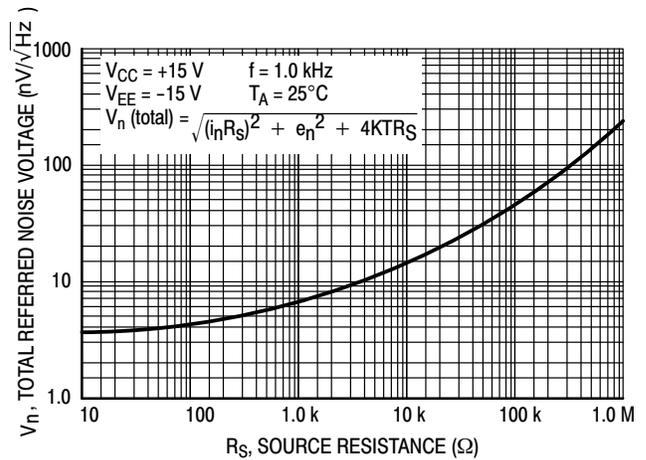**Figure 30. Input Referred Noise Voltage and Current versus Frequency**



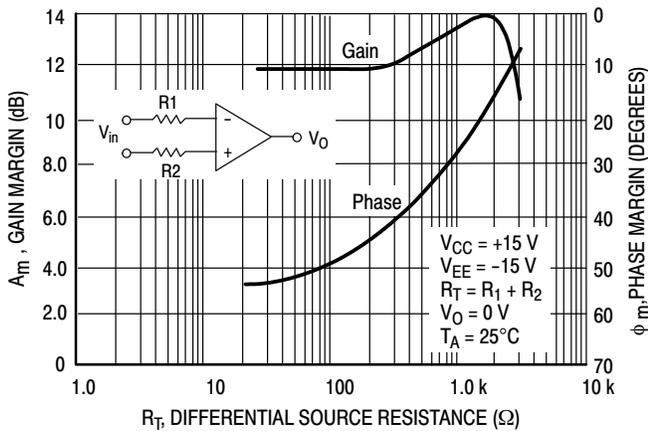**Figure 31. Total Input Referred Noise Voltage versus Source Resistant**



**Figure 32. Phase Margin and Gain Margin versus Differential Source Resistance**
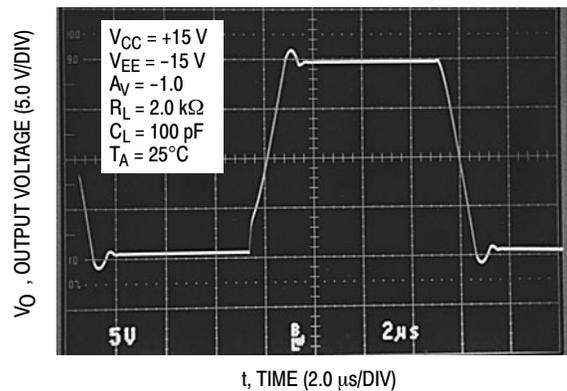


**Figure 33. Inverting Amplifier Slew Rate**

V_O, OUTPUT VOLTAGE (5.0 V/DIV)

$V_{CC} = +15$ V
$V_{EE} = -15$ V
$A_V = +1.0$
$R_L = 2.0$ kΩ
$C_L = 100$ pF
$T_A = 25°C$

t, TIME (2.0 μs/DIV)
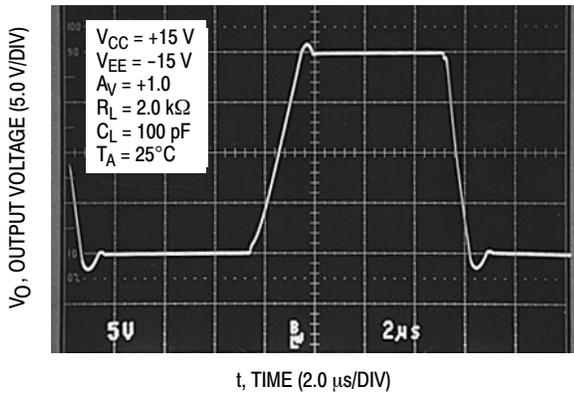
**Figure 34. Non−inverting Amplifier Slew Rate**



V_O, OUTPUT VOLTAGE (5.0 V/DIV)

$C_L = 100$ pF

$V_{CC} = +15$ V
$V_{EE} = -15$ V
$A_V = +1.0$
$R_L = 2.0$ kΩ
$T_A = 25°C$

$C_L = 0$ pF

t, TIME (200 ns/DIV)
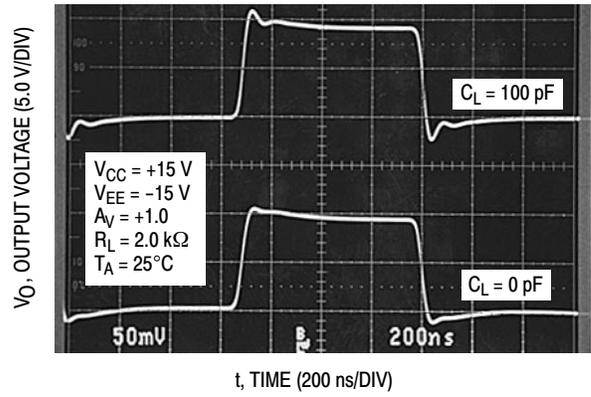
**Figure 35. Non−inverting Amplifier Overshoot**



e_n, INPUT NOISE VOLTAGE (100nV/DIV)

$V_{CC} = +15$ V
$V_{EE} = -15$ V
BW = 0.1 Hz to 10 Hz
$T_A = 25°C$
See Noise Circuit
(Figure 36)

t, TIME (1.0 sec/DIV)

**Figure 36. Low Frequency Noise Voltage
versus Time**

## APPLICATIONS INFORMATION

The MC33077 is designed primarily for its low noise, low offset voltage, high gain bandwidth product and large output swing characteristics. Its outstanding high frequency gain/phase performance make it a very attractive amplifier for high quality preamps, instrumentation amps, active filters and other applications requiring precision quality characteristics.
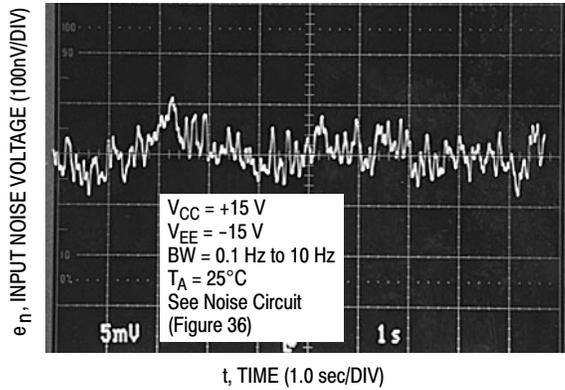
The MC33077 utilizes high frequency lateral PNP input transistors in a low noise bipolar differential stage driving a compensated Miller integration amplifier. Dual-doublet frequency compensation techniques are used to enhance the gain bandwidth product. The output stage uses an all NPN transistor design which provides greater output voltage swing and improved frequency performance over more conventional stages by using both PNP and NPN transistors (Class AB). This combination produces an amplifier with superior characteristics.

Through precision component matching and innovative current mirror design, a lower than normal temperature coefficient of input offset voltage (2.0 μV/°C as opposed to 10 μV/°C), as well as low input offset voltage, is accomplished.

The minimum common mode input range is from 1.5 V below the positive rail ($V_{CC}$) to 1.5 V above the negative rail ($V_{EE}$). The inputs will typically common mode to within 1.0 V of both negative and positive rails though degradation in offset voltage and gain will be experienced as the common mode voltage nears either supply rail. In practice, though not recommended, the input voltage may exceed $V_{CC}$ by approximately 3.0 V and decrease below the $V_{EE}$ by approximately 0.6 V without causing permanent damage to the device. If the input voltage on either or both inputs is less than approximately 0.6 V, excessive current may flow, if not limited, causing permanent damage to the device.

The amplifier will not latch with input source currents up to 20 mA, though in practice, source currents should be limited to 5.0 mA to avoid any parametric damage to the device. If both inputs exceed $V_{CC}$, the output will be in the high state and phase reversal may occur. No phase reversal will occur if the voltage on one input is within the common mode range and the voltage on the other input exceeds $V_{CC}$. Phase reversal may occur if the input voltage on either or both inputs is less than 1.0 V above the negative rail. Phase reversal will be experienced if the voltage on either or both inputs is less than $V_{EE}$.

Through the use of dual-doublet frequency compensation techniques, the gain bandwidth product has been greatly enhanced over other amplifiers using the conventional single pole compensation. The phase and gain error of the amplifier remains low to higher frequencies for fixed amplifier gain configurations.

With the all NPN output stage, there is minimal swing loss to the supply rails, producing superior output swing, no crossover distortion and improved output phase symmetry with output voltage excursions (output phase symmetry being the amplifiers ability to maintain a constant phase relation independent of its output voltage swing). Output phase symmetry degradation in the more conventional PNP and NPN transistor output stage was primarily due to the inherent cut-off frequency mismatch of the PNP and NPN transistors used (typically 10 MHz and 300 MHz, respectively), causing considerable phase change to occur as the output voltage changes. By eliminating the PNP in the output, such phase change has been avoided and a very significant improvement in output phase symmetry as well as output swing has been accomplished.

The output swing improvement is most noticeable when operation is with lower supply voltages (typically 30% with ± 5.0 V supplies). With a 10 k load, the output of the amplifier can typically swing to within 1.0 V of the positive rail ($V_{CC}$), and to within 0.3 V of the negative rail ($V_{EE}$), producing a 28.7 $V_{pp}$ signal from ±15 V supplies. Output voltage swing can be further improved by using an output pull-up resistor referenced to the $V_{CC}$. Where output signals are referenced to the positive supply rail, the pull-up resistor will pull the output to $V_{CC}$ during the positive swing, and during the negative swing, the NPN output transistor collector will pull the output very near $V_{EE}$. This configuration will produce the maximum attainable output signal from given supply voltages. The value of load resistance used should be much less than any feedback resistance to avoid excess loading and allow easy pull-up of the output.

Output impedance of the amplifier is typically less than 50 Ω at frequencies less than the unity gain crossover frequency (see Figure 19). The amplifier is unity gain stable with output capacitance loads up to 500 pF at full output swing over the −55 °C to +125 °C temperature range. Output phase symmetry is excellent with typically 4 °C total phase change over a 20 V output excursion at 25 °C with a 2.0 kΩ and 100 pF load. With a 2.0 kΩ resistive load and no capacitance loading, the total phase change is approximately one degree for the same 20 V output excursion. With a 2.0 kΩ and 500 pF load at 125 °C, the total phase change is typically only 10 °C for a 20 V output excursion (see Figure 28).

As with all amplifiers, care should be exercised to insure that one does not create a pole at the input of the amplifier which is near the closed loop corner frequency. This becomes a greater concern when using high frequency amplifiers since it is very easy to create such a pole with relatively small values of resistance on the inputs. If this does occur, the amplifier's phase will degrade severely causing the amplifier to become unstable. Effective source resistances, acting in conjunction with the input capacitance of the amplifier, should be kept to a minimum to avoid creating such a pole at the input (see Figure 32). There is minimal effect on stability where the created input pole is much greater than the closed loop corner frequency. Where amplifier stability is affected as a result of a negative feedback resistor in conjunction with the

amplifier's input capacitance, creating a pole near the closed loop corner frequency, lead capacitor compensation techniques (lead capacitor in parallel with the feedback resistor) can be employed to improve stability. The feedback resistor and lead capacitor RC time constant should be larger than that of the uncompensated input pole frequency. Having a high resistance connected to the noninverting input of the amplifier can create a like instability problem. Compensation for this condition can be accomplished by adding a lead capacitor in parallel with the noninverting input resistor of such a value as to make the RC time constant larger than the RC time constant of the uncompensated input resistor acting in conjunction with the amplifiers input capacitance.

For optimum frequency performance and stability, careful component placement and printed circuit board layout should be exercised. For example, long unshielded input or output leads may result in unwanted input output coupling. In order to reduce the input capacitance, the body of resistors connected to the input pins should be physically close to the input pins. This not only minimizes the input pole creation for optimum frequency response, but also minimizes extraneous signal "pickup" at this node. Power supplies should be decoupled with adequate capacitance as close as possible to the device supply pin.

In addition to amplifier stability considerations, input source resistance values should be low to take full advantage of the low noise characteristics of the amplifier. Thermal noise (Johnson Noise) of a resistor is generated by thermally-charged carriers randomly moving within the resistor creating a voltage. The RMS thermal noise voltage in a resistor can be calculated from:

$$E_{nr} = \sqrt{4k\,TR \times BW}$$

where:

  k = Boltzmann's Constant ($1.38 \times 10^{-23}$ joules/k)
  T = Kelvin temperature
  R = Resistance in ohms
  BW = Upper and lower frequency limit in Hertz.

By way of reference, a 1.0 kΩ resistor at 25 °C will produce a 4.0 nV/$\sqrt{Hz}$ of RMS noise voltage. If this resistor is connected to the input of the amplifier, the noise voltage will be gained-up in accordance to the amplifier's gain configuration. For this reason, the selection of input source resistance for low noise circuit applications warrants serious consideration. The total noise of the amplifier, as referred to its inputs, is typically only 4.4 nV/$\sqrt{Hz}$ at 1.0 kHz.

The output of any one amplifier is current limited and thus protected from a direct short to ground, However, under such conditions, it is important not to allow the amplifier to exceed the maximum junction temperature rating. Typically for ±15 V supplies, any one output can be shorted continuously to ground without exceeding the temperature rating.
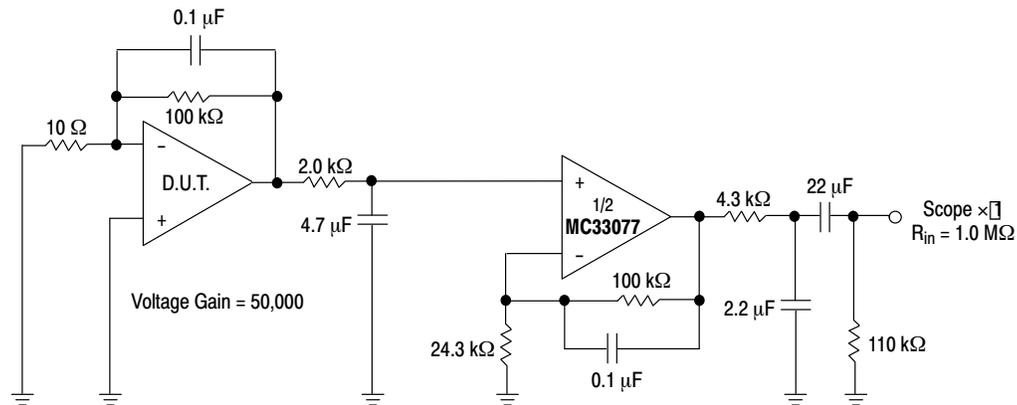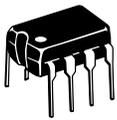


Note: All capacitors are non-polarized.

**Figure 37. Voltage Noise Test Circuit**
**(0.1 Hz to 10 Hz$_{p-p}$)**

# MC33077

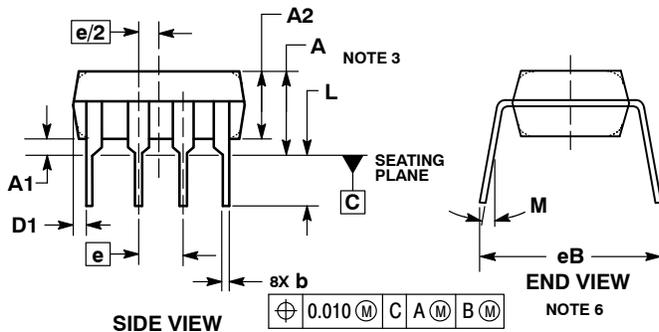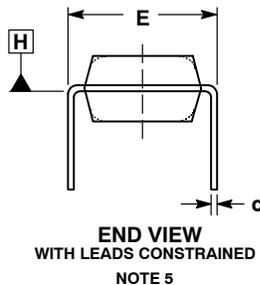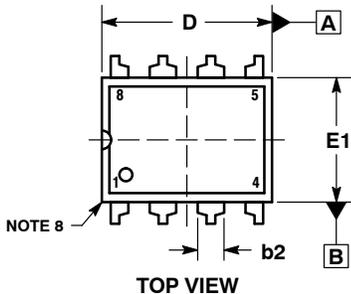| Revision | Description of Changes | Date |
|----------|------------------------|------|
| 6 | Rebranded the Data Sheet to **onsemi** format.<br>MC33077D, MC33077DR2, MC33077P OPNs Marked as Discontinued. | 07/29/2025 |

This document has undergone updates prior to the inclusion of this revision history table. The changes tracked here only reflect updates made on the noted approval dates.
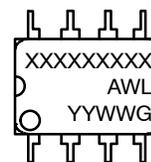
**PDIP−8**
CASE 626−05
ISSUE P

DATE 22 APR 2015

**SCALE 1:1**

**TOP VIEW**

NOTE 8

**END VIEW**
**WITH LEADS CONSTRAINED**
**NOTE 5**

**SIDE VIEW**

8X b

⊕ | 0.010 Ⓜ | C | A Ⓜ | B Ⓜ

**END VIEW**
**NOTE 6**

NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
2. CONTROLLING DIMENSION: INCHES.
3. DIMENSIONS A, A1 AND L ARE MEASURED WITH THE PACK-AGE SEATED IN JEDEC SEATING PLANE GAUGE GS−3.
4. DIMENSIONS D, D1 AND E1 DO NOT INCLUDE MOLD FLASH OR PROTRUSIONS. MOLD FLASH OR PROTRUSIONS ARE NOT TO EXCEED 0.10 INCH.
5. DIMENSION E IS MEASURED AT A POINT 0.015 BELOW DATUM PLANE H WITH THE LEADS CONSTRAINED PERPENDICULAR TO DATUM C.
6. DIMENSION eB IS MEASURED AT THE LEAD TIPS WITH THE LEADS UNCONSTRAINED.
7. DATUM PLANE H IS COINCIDENT WITH THE BOTTOM OF THE LEADS, WHERE THE LEADS EXIT THE BODY.
8. PACKAGE CONTOUR IS OPTIONAL (ROUNDED OR SQUARE CORNERS).

| DIM | INCHES | | MILLIMETERS | |
|---|---|---|---|---|
| | MIN | MAX | MIN | MAX |
| A | ---- | 0.210 | --- | 5.33 |
| A1 | 0.015 | ---- | 0.38 | --- |
| A2 | 0.115 | 0.195 | 2.92 | 4.95 |
| b | 0.014 | 0.022 | 0.35 | 0.56 |
| b2 | 0.060 TYP | | 1.52 TYP | |
| C | 0.008 | 0.014 | 0.20 | 0.36 |
| D | 0.355 | 0.400 | 9.02 | 10.16 |
| D1 | 0.005 | ---- | 0.13 | --- |
| E | 0.300 | 0.325 | 7.62 | 8.26 |
| E1 | 0.240 | 0.280 | 6.10 | 7.11 |
| e | 0.100 BSC | | 2.54 BSC | |
| eB | ---- | 0.430 | --- | 10.92 |
| L | 0.115 | 0.150 | 2.92 | 3.81 |
| M | ---- | 10° | --- | 10° |

STYLE 1:
PIN 1. AC IN
2. DC + IN
3. DC − IN
4. AC IN
5. GROUND
6. OUTPUT
7. AUXILIARY
8. $V_{CC}$

**GENERIC**
**MARKING DIAGRAM***

XXXXXXXXX
AWL
YYWWG

| XXXX | = Specific Device Code |
|---|---|
| A | = Assembly Location |
| WL | = Wafer Lot |
| YY | = Year |
| WW | = Work Week |
| G | = Pb−Free Package |

*This information is generic. Please refer to device data sheet for actual part marking. Pb−Free indicator, "G" or microdot "■", may or may not be present. Some products may not follow the Generic Marking.

| DOCUMENT NUMBER: | 98ASB42420B | | |
|---|---|---|---|
| DESCRIPTION: | PDIP−8 | | PAGE 1 OF 1 |

**SOIC−8 NB**
CASE 751−07
ISSUE AK

DATE 16 FEB 2011

8

1

**SCALE 1:1**

−X−

A

8    5

B    S

−Y−

4

G

$\oplus$ | 0.25 (0.010) Ⓜ | Y Ⓜ

C

SEATING PLANE

−Z−

$\bigtriangleup$ | 0.10 (0.004)
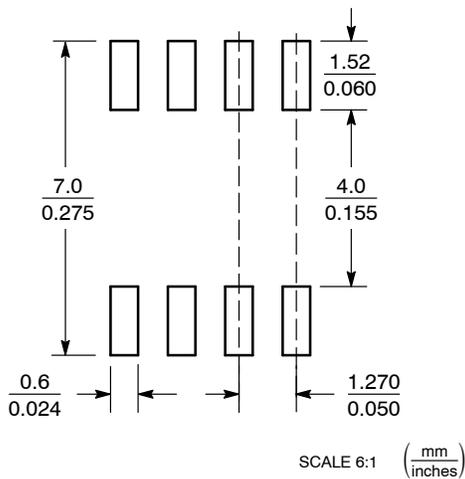
H    D

$\oplus$ | 0.25 (0.010)Ⓜ | Z | Y Ⓢ | X Ⓢ

K

N X 45°

M    J

NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: MILLIMETER.
3. DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
4. MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE.
5. DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.
6. 751−01 THRU 751−06 ARE OBSOLETE. NEW STANDARD IS 751−07.

| DIM | MILLIMETERS | | INCHES | |
|-----|-----|-----|-----|-----|
| | MIN | MAX | MIN | MAX |
| A | 4.80 | 5.00 | 0.189 | 0.197 |
| B | 3.80 | 4.00 | 0.150 | 0.157 |
| C | 1.35 | 1.75 | 0.053 | 0.069 |
| D | 0.33 | 0.51 | 0.013 | 0.020 |
| G | 1.27 BSC | | 0.050 BSC | |
| H | 0.10 | 0.25 | 0.004 | 0.010 |
| J | 0.19 | 0.25 | 0.007 | 0.010 |
| K | 0.40 | 1.27 | 0.016 | 0.050 |
| M | 0 ° | 8 ° | 0 ° | 8 ° |
| N | 0.25 | 0.50 | 0.010 | 0.020 |
| S | 5.80 | 6.20 | 0.228 | 0.244 |

### SOLDERING FOOTPRINT*

1.52 / 0.060

7.0 / 0.275

4.0 / 0.155

0.6 / 0.024

1.270 / 0.050

SCALE 6:1    $\left(\dfrac{mm}{inches}\right)$

### GENERIC
### MARKING DIAGRAM*

8

XXXXX
ALYWX

1

**IC**

8

XXXXX
ALYWX ▪

1

**IC**
**(Pb−Free)**

8

XXXXXX
AYWW

1

**Discrete**

8

XXXXXX
AYWW ▪

1

**Discrete**
**(Pb−Free)**

XXXXX = Specific Device Code
A = Assembly Location
L = Wafer Lot
Y = Year
W = Work Week
▪ = Pb−Free Package

XXXXXX = Specific Device Code
A = Assembly Location
Y = Year
WW = Work Week
▪ = Pb−Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb−Free indicator, "G" or microdot "▪", may or may not be present. Some products may not follow the Generic Marking.

*For additional information on our Pb−Free strategy and soldering details, please download the **onsemi** Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

## STYLES ON PAGE 2

# SOIC−8 NB
## CASE 751−07
## ISSUE AK

DATE 16 FEB 2011

**STYLE 1:**
PIN 1. EMITTER
2. COLLECTOR
3. COLLECTOR
4. EMITTER
5. EMITTER
6. BASE
7. BASE
8. EMITTER

**STYLE 2:**
PIN 1. COLLECTOR, DIE, #1
2. COLLECTOR, #1
3. COLLECTOR, #2
4. COLLECTOR, #2
5. BASE, #2
6. EMITTER, #2
7. BASE, #1
8. EMITTER, #1

**STYLE 3:**
PIN 1. DRAIN, DIE #1
2. DRAIN, #1
3. DRAIN, #2
4. DRAIN, #2
5. GATE, #2
6. SOURCE, #2
7. GATE, #1
8. SOURCE, #1

**STYLE 4:**
PIN 1. ANODE
2. ANODE
3. ANODE
4. ANODE
5. ANODE
6. ANODE
7. ANODE
8. COMMON CATHODE

**STYLE 5:**
PIN 1. DRAIN
2. DRAIN
3. DRAIN
4. DRAIN
5. GATE
6. GATE
7. SOURCE
8. SOURCE

**STYLE 6:**
PIN 1. SOURCE
2. DRAIN
3. DRAIN
4. SOURCE
5. SOURCE
6. GATE
7. GATE
8. SOURCE

**STYLE 7:**
PIN 1. INPUT
2. EXTERNAL BYPASS
3. THIRD STAGE SOURCE
4. GROUND
5. DRAIN
6. GATE 3
7. SECOND STAGE Vd
8. FIRST STAGE Vd

**STYLE 8:**
PIN 1. COLLECTOR, DIE #1
2. BASE, #1
3. BASE, #2
4. COLLECTOR, #2
5. COLLECTOR, #2
6. EMITTER, #2
7. EMITTER, #1
8. COLLECTOR, #1

**STYLE 9:**
PIN 1. EMITTER, COMMON
2. COLLECTOR, DIE #1
3. COLLECTOR, DIE #2
4. EMITTER, COMMON
5. EMITTER, COMMON
6. BASE, DIE #2
7. BASE, DIE #1
8. EMITTER, COMMON

**STYLE 10:**
PIN 1. GROUND
2. BIAS 1
3. OUTPUT
4. GROUND
5. GROUND
6. BIAS 2
7. INPUT
8. GROUND

**STYLE 11:**
PIN 1. SOURCE 1
2. GATE 1
3. SOURCE 2
4. GATE 2
5. DRAIN 2
6. DRAIN 2
7. DRAIN 1
8. DRAIN 1

**STYLE 12:**
PIN 1. SOURCE
2. SOURCE
3. SOURCE
4. GATE
5. DRAIN
6. DRAIN
7. DRAIN
8. DRAIN

**STYLE 13:**
PIN 1. N.C.
2. SOURCE
3. SOURCE
4. GATE
5. DRAIN
6. DRAIN
7. DRAIN
8. DRAIN

**STYLE 14:**
PIN 1. N−SOURCE
2. N−GATE
3. P−SOURCE
4. P−GATE
5. P−DRAIN
6. P−DRAIN
7. N−DRAIN
8. N−DRAIN

**STYLE 15:**
PIN 1. ANODE 1
2. ANODE 1
3. ANODE 1
4. ANODE 1
5. CATHODE, COMMON
6. CATHODE, COMMON
7. CATHODE, COMMON
8. CATHODE, COMMON

**STYLE 16:**
PIN 1. EMITTER, DIE #1
2. BASE, DIE #1
3. EMITTER, DIE #2
4. BASE, DIE #2
5. COLLECTOR, DIE #2
6. COLLECTOR, DIE #2
7. COLLECTOR, DIE #1
8. COLLECTOR, DIE #1

**STYLE 17:**
PIN 1. VCC
2. V2OUT
3. V1OUT
4. TXE
5. RXE
6. VEE
7. GND
8. ACC

**STYLE 18:**
PIN 1. ANODE
2. ANODE
3. SOURCE
4. GATE
5. DRAIN
6. DRAIN
7. CATHODE
8. CATHODE

**STYLE 19:**
PIN 1. SOURCE 1
2. GATE 1
3. SOURCE 2
4. GATE 2
5. DRAIN 2
6. MIRROR 2
7. DRAIN 1
8. MIRROR 1

**STYLE 20:**
PIN 1. SOURCE (N)
2. GATE (N)
3. SOURCE (P)
4. GATE (P)
5. DRAIN
6. DRAIN
7. DRAIN
8. DRAIN

**STYLE 21:**
PIN 1. CATHODE 1
2. CATHODE 2
3. CATHODE 3
4. CATHODE 4
5. CATHODE 5
6. COMMON ANODE
7. COMMON ANODE
8. CATHODE 6

**STYLE 22:**
PIN 1. I/O LINE 1
2. COMMON CATHODE/VCC
3. COMMON CATHODE/VCC
4. I/O LINE 3
5. COMMON ANODE/GND
6. I/O LINE 4
7. I/O LINE 5
8. COMMON ANODE/GND

**STYLE 23:**
PIN 1. LINE 1 IN
2. COMMON ANODE/GND
3. COMMON ANODE/GND
4. LINE 2 IN
5. LINE 2 OUT
6. COMMON ANODE/GND
7. COMMON ANODE/GND
8. LINE 1 OUT

**STYLE 24:**
PIN 1. BASE
2. EMITTER
3. COLLECTOR/ANODE
4. COLLECTOR/ANODE
5. CATHODE
6. CATHODE
7. COLLECTOR/ANODE
8. COLLECTOR/ANODE

**STYLE 25:**
PIN 1. VIN
2. N/C
3. REXT
4. GND
5. IOUT
6. IOUT
7. IOUT
8. IOUT

**STYLE 26:**
PIN 1. GND
2. dv/dt
3. ENABLE
4. ILIMIT
5. SOURCE
6. SOURCE
7. SOURCE
8. VCC

**STYLE 27:**
PIN 1. ILIMIT
2. OVLO
3. UVLO
4. INPUT+
5. SOURCE
6. SOURCE
7. SOURCE
8. DRAIN

**STYLE 28:**
PIN 1. SW_TO_GND
2. DASIC_OFF
3. DASIC_SW_DET
4. GND
5. V_MON
6. VBULK
7. VBULK
8. VIN

**STYLE 29:**
PIN 1. BASE, DIE #1
2. EMITTER, #1
3. BASE, #2
4. EMITTER, #2
5. COLLECTOR, #2
6. COLLECTOR, #2
7. COLLECTOR, #1
8. COLLECTOR, #1

**STYLE 30:**
PIN 1. DRAIN 1
2. DRAIN 1
3. GATE 2
4. SOURCE 2
5. SOURCE 1/DRAIN 2
6. SOURCE 1/DRAIN 2
7. SOURCE 1/DRAIN 2
8. GATE 1

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|---|---|---|---|
| DESCRIPTION: | SOIC−8 NB | | PAGE 2 OF 2 |

## ADDITIONAL INFORMATION

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